

PointProbe® Plus Non-Contact /Tapping Mode - Long Cantilever

The PointProbe® Plus (PPP) combines high application versatility and compatibility with most commercial SPMs. The typical AFM tip radius of less than 7 nm and the minimized variation in AFM tip shape provide reproducible images and enhanced resolution.

NANOSENSORS™ PPP-NCL AFM probes are designed for non-contact mode or tapping mode AFM (also known as: attractive or dynamic mode). The NCL type is offered as an alternative to NANOSENSORS™ high frequency non contact type (NCH). PPP-NCL is recommended if the feedback loop of the microscope does not accept high frequencies (400 kHz) or if the detection system needs a minimum AFM cantilever length > 125 µm. Compared to the high frequency non-contact type NCH the maximum scanning speed is slightly reduced. This AFM probe type combines high operation stability with outstanding sensitivity and fast scanning ability.

The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 10 nm
- AFM tip height 10 - 15 µm
- highly doped silicon to dissipate static charge
- chemically inert
- high mechanical Q-factor for high sensitivity
- alignment grooves on backside of silicon holder chip
- precise alignment of the AFM cantilever position (within +/- 2 µm) when used with the Alignment Chip
- compatible with PointProbe® Plus XY-Alignment Series

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	190	146 - 236
Force Constant [N/m]	48	21 - 98
Length [µm]	225	215 - 235
Mean Width [µm]	38	30 - 45
Thickness [µm]	7	6 - 8

Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PPP-NCL-10	10	of all probes
PPP-NCL-20	20	of all probes
PPP-NCL-50	50
PPP-NCL-W	380	of up to 32 probes